

Special Issue

Computer Vision Applied for Industry 4.0

Message from the Guest Editors

With the high volume of data available in industrial processes, the application of computer vision can be an excellent alternative capable of detecting and signaling process anomalies, contributing to quick and assertive decision-making, reducing the probability of human errors, and increasing process efficiency. Therefore, this Special Issue is intended to present new ideas and experimental results in the field of computer vision applied to industry 4.0, from the theory, design, and development to practical applications. **Keywords:**

- computer vision
- machine vision
- Industry 4.0
- smart manufacturing
- smart factory
- process monitoring
- measurement
- quality control
- artificial intelligence
- big data

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Deadline for manuscript submissions

closed (10 July 2023)



Applied Sciences

an Open Access Journal
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Impact Factor 2.5
CiteScore 5.5



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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